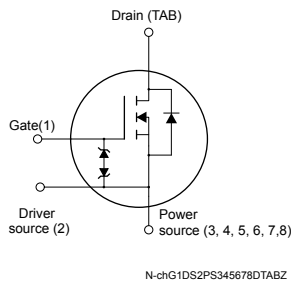
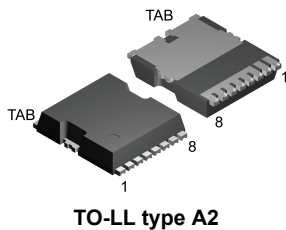


N-channel 600 V, 48 mΩ typ., 34 A MDmesh M6 Power MOSFET in a TO-LL package



Features

Order code	V _{DS}	R _{DS(on)} max.	I _D
STO67N60M6	600 V	54 mΩ	34 A

- Reduced switching losses
- Lower R_{DS(on)} per area vs previous generation
- Low gate input resistance
- 100% avalanche tested
- Zener-protected
- High creepage package
- Excellent switching performance thanks to the extra driving source pin

Applications

- Switching applications
- LLC converters
- Boost PFC converters

Description

The new MDmesh M6 technology incorporates the most recent advancements to the well-known and consolidated MDmesh family of SJ MOSFETs. STMicroelectronics builds on the previous generation of MDmesh devices through its new M6 technology, which combines excellent R_{DS(on)} per area improvement with one of the most effective switching behaviors available, as well as a user-friendly experience for maximum end-application efficiency.

Product status link

[STO67N60M6](#)

Device summary

Order code	STO67N60M6
Marking	67N60M6
Package	TO-LL type A2
Packing	Tape and reel

1 Electrical ratings

Table 1. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{GS}	Gate-source voltage	± 25	V
I_D	Drain current (continuous) at $T_C = 25\text{ }^{\circ}\text{C}$	34	A
	Drain current (continuous) at $T_C = 100\text{ }^{\circ}\text{C}$	21	A
$I_{DM}^{(1)}$	Drain current (pulsed)	200	A
P_{TOT}	Total power dissipation at $T_C = 25\text{ }^{\circ}\text{C}$	150	W
$dv/dt^{(2)}$	Peak diode recovery voltage slope	15	V/ns
$dv/dt^{(3)}$	MOSFET dv/dt ruggedness	100	V/ns
T_{stg}	Storage temperature range	-55 to 150	$^{\circ}\text{C}$
T_J	Operating junction temperature range		$^{\circ}\text{C}$

1. Pulse width is limited by safe operating area.
2. $I_{SD} \leq 34\text{ A}$, $di/dt \leq 400\text{ A}/\mu\text{s}$, $V_{DS}(\text{peak}) < V_{(BR)DSS}$, $V_{DD} = 400\text{ V}$
3. $V_{DS} \leq 480\text{ V}$

Table 2. Thermal data

Symbol	Parameter	Value	Unit
R_{thJC}	Thermal resistance, junction-to-case	0.83	$^{\circ}\text{C}/\text{W}$
R_{thJA}	Thermal resistance, junction-to-ambient ⁽¹⁾	43	$^{\circ}\text{C}/\text{W}$
	Thermal resistance, junction-to-ambient ⁽²⁾	22	

1. When mounted on 1 inch² FR-4 pcb, standard footprint 2 Oz copper board.
2. When mounted on 40x40mm FR-4 pcb, 6 cm² 2 Oz copper board.

Table 3. Avalanche characteristics

Symbol	Parameter	Value	Unit
I_{AR}	Avalanche current, repetitive or not repetitive (pulse width limited by T_J max.)	6	A
E_{AS}	Single pulse avalanche energy (starting $T_J = 25\text{ }^{\circ}\text{C}$, $I_D = I_{AR}$, $V_{DD} = 50\text{ V}$)	760	mJ

2 Electrical characteristics

$T_C = 25\text{ }^{\circ}\text{C}$ unless otherwise specified.

Table 4. On /off-states

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	$V_{GS} = 0\text{ V}$, $I_D = 1\text{ mA}$	600			V
I_{DSS}	Zero-gate voltage drain current	$V_{GS} = 0\text{ V}$, $V_{DS} = 600\text{ V}$			1	μA
		$V_{GS} = 0\text{ V}$, $V_{DS} = 600\text{ V}$, $T_C = 125\text{ }^{\circ}\text{C}^{(1)}$			100	
I_{GSS}	Gate-body leakage current	$V_{DS} = 0\text{ V}$, $V_{GS} = \pm 25\text{ V}$			± 5	μA
$V_{GS(th)}$	Gate threshold voltage	$V_{DS} = V_{GS}$, $I_D = 250\text{ }\mu\text{A}$	3.25	4.00	4.75	V
$R_{DS(on)}$	Static drain-source on-resistance	$V_{GS} = 10\text{ V}$, $I_D = 26\text{ A}$		48	54	m Ω

1. Defined by design, not subject to production test.

Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C_{iss}	Input capacitance	$V_{GS} = 0\text{ V}$, $V_{DS} = 100\text{ V}$, $f = 1\text{ MHz}$	-	3400	-	pF
C_{oss}	Output capacitance		-	280	-	pF
C_{rss}	Reverse transfer capacitance		-	2	-	pF
$C_{oss\text{ eq.}}^{(1)}$	Equivalent output capacitance	$V_{GS} = 0\text{ V}$, $V_{DS} = 0\text{ to }480\text{ V}$	-	520	-	pF
R_G	Intrinsic gate resistance	$f = 1\text{ MHz}$ open drain	-	1.4	-	Ω
Q_g	Total gate charge	$V_{DD} = 480\text{ V}$, $I_D = 52\text{ A}$, $V_{GS} = 0\text{ to }10\text{ V}$ (see Figure 14. Test circuit for gate charge behavior)	-	72.5	-	nC
Q_{gs}	Gate-source charge		-	24.5	-	nC
Q_{gd}	Gate-drain charge		-	28.5	-	nC

1. $C_{oss\text{ eq.}}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS} .

Table 6. Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 300\text{ V}$, $I_D = 26\text{ A}$, $R_G = 4.7\text{ }\Omega$, $V_{GS} = 10\text{ V}$	-	24.5	-	ns
t_r	Rise time		-	35	-	ns
$t_{d(off)}$	Turn-off delay time	(see Figure 13. Switching times test circuit for resistive load and Figure 18. Switching time waveform)	-	72	-	ns
t_f	Fall time		-	10.5	-	ns

Table 7. Source-drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
I_{SD}	Source-drain current		-		34	A
$I_{SDM}^{(1)}$	Source-drain current (pulsed)		-		200	A
$V_{SD}^{(2)}$	Forward on voltage	$V_{GS} = 0\text{ V}$, $I_{SD} = 52\text{ A}$	-		1.6	V
t_{rr}	Reverse recovery time	$I_{SD} = 52\text{ A}$, $di/dt = 100\text{ A}/\mu\text{s}$, $V_{DD} = 60\text{ V}$ (see Figure 15. Test circuit for inductive load switching and diode recovery times)	-	348		ns
Q_{rr}	Reverse recovery charge		-	5.6		μC
I_{RRM}	Reverse recovery current		-	32		A
t_{rr}	Reverse recovery time	$I_{SD} = 52\text{ A}$, $di/dt = 100\text{ A}/\mu\text{s}$, $V_{DD} = 60\text{ V}$, $T_J = 150\text{ }^\circ\text{C}$ (see Figure 15. Test circuit for inductive load switching and diode recovery times)	-	484		ns
Q_{rr}	Reverse recovery charge		-	10.6		μC
I_{RRM}	Reverse recovery current		-	44		A

1. Pulse width is limited by safe operating area.
2. Pulse test: pulse duration = 300 μs , duty cycle 1.5%.

2.1 Electrical characteristics (curves)

Figure 1. Safe operating area

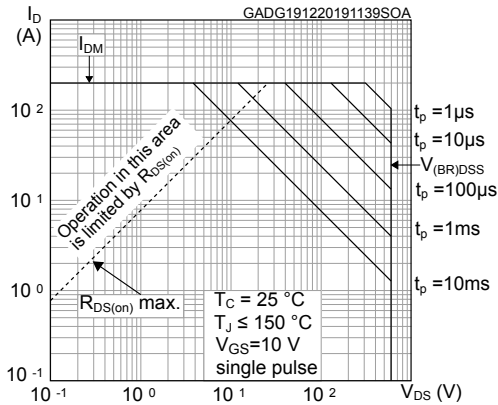


Figure 2. Maximum transient thermal impedance

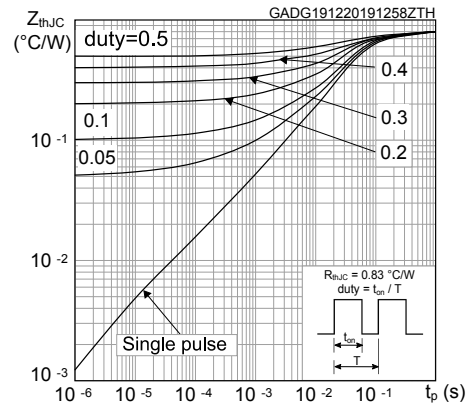


Figure 3. Typical output characteristics

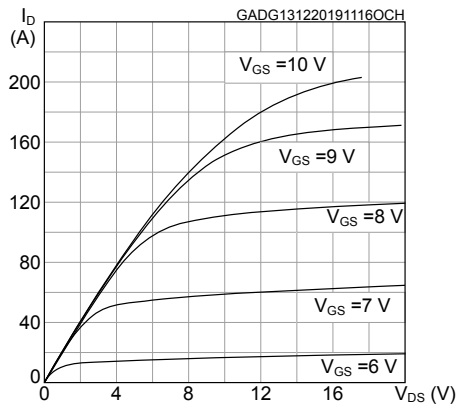


Figure 4. Typical transfer characteristics

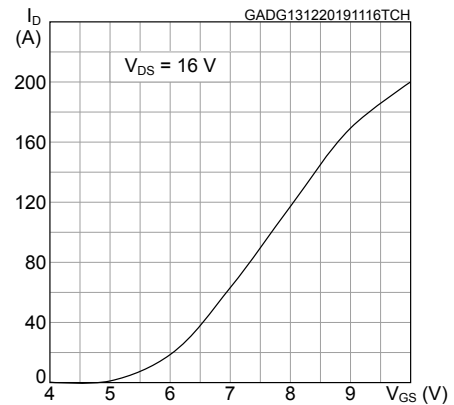


Figure 5. Typical gate charge characteristics

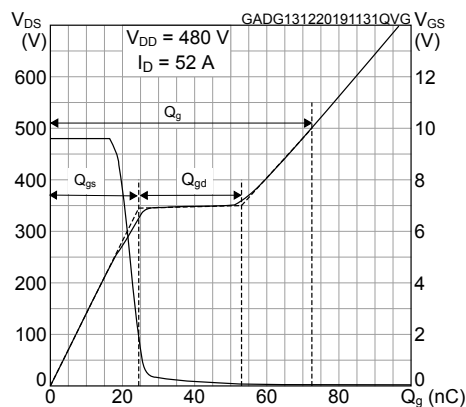


Figure 6. Typical drain-source on-resistance

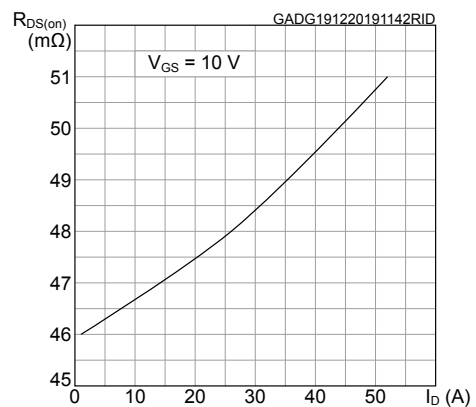


Figure 7. Typical capacitance characteristics

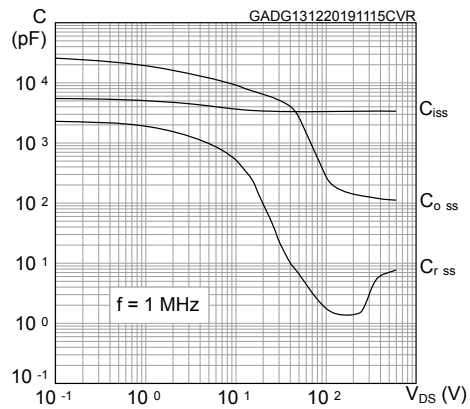


Figure 8. Normalized gate threshold vs. temperature

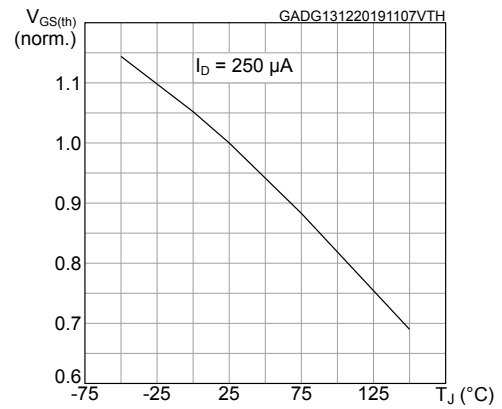


Figure 9. Normalized on-resistance vs. temperature

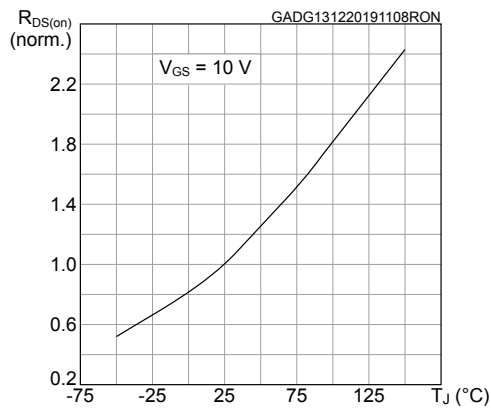


Figure 10. Normalized breakdown voltage vs temperature

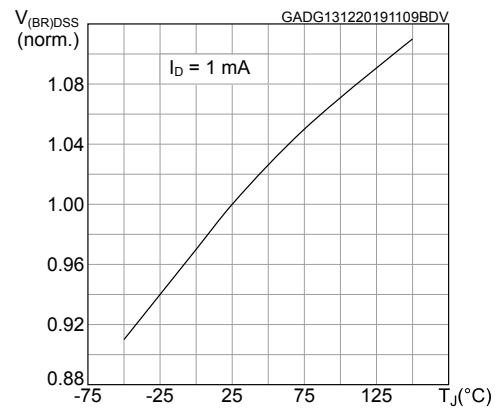


Figure 11. Output capacitance stored energy

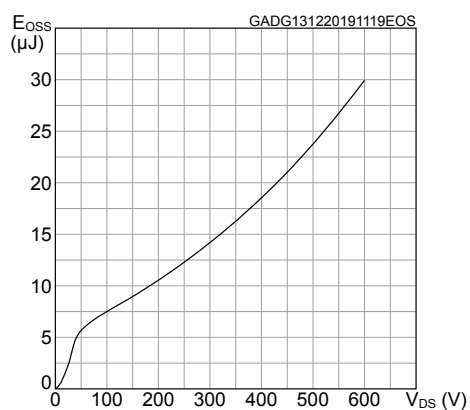
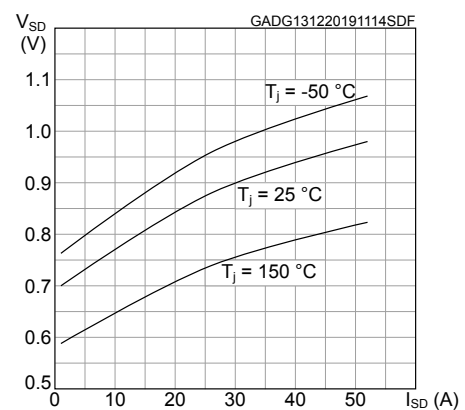
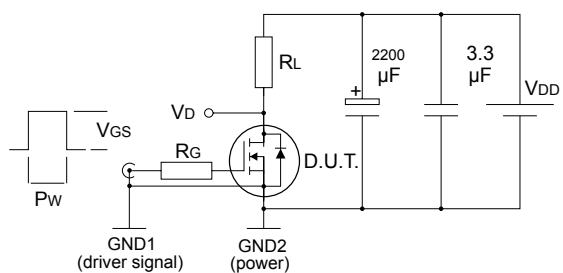


Figure 12. Typical reverse diode forward characteristics



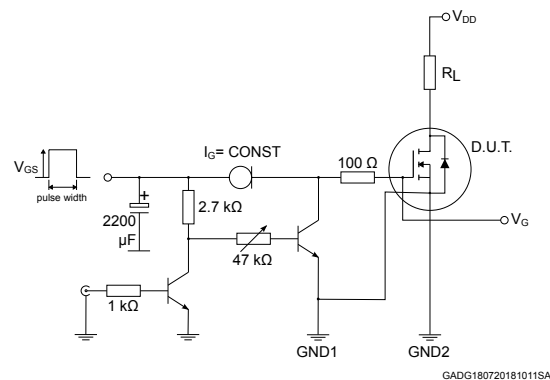
3 Test circuits

Figure 13. Switching times test circuit for resistive load



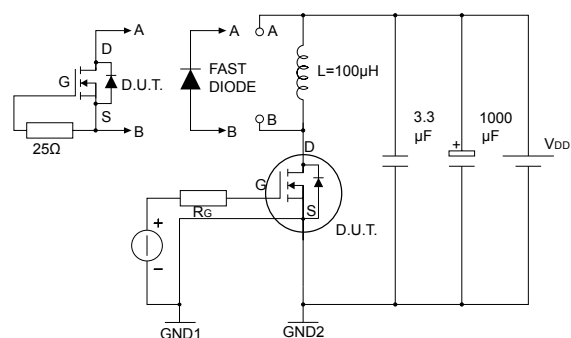
AM15855v1

Figure 14. Test circuit for gate charge behavior



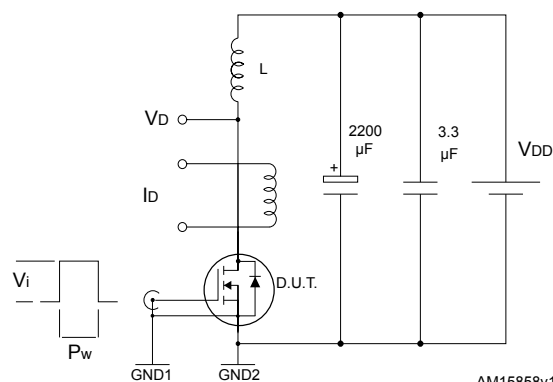
GADG180720181011SA

Figure 15. Test circuit for inductive load switching and diode recovery times



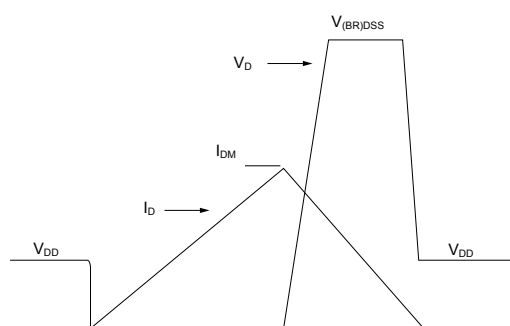
AM15857v1

Figure 16. Unclamped inductive load test circuit



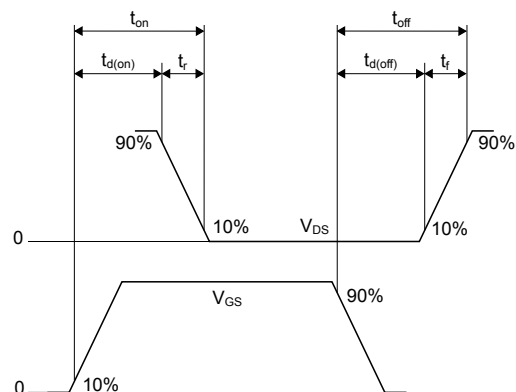
AM15858v1

Figure 17. Unclamped inductive waveform



AM01472v1

Figure 18. Switching time waveform



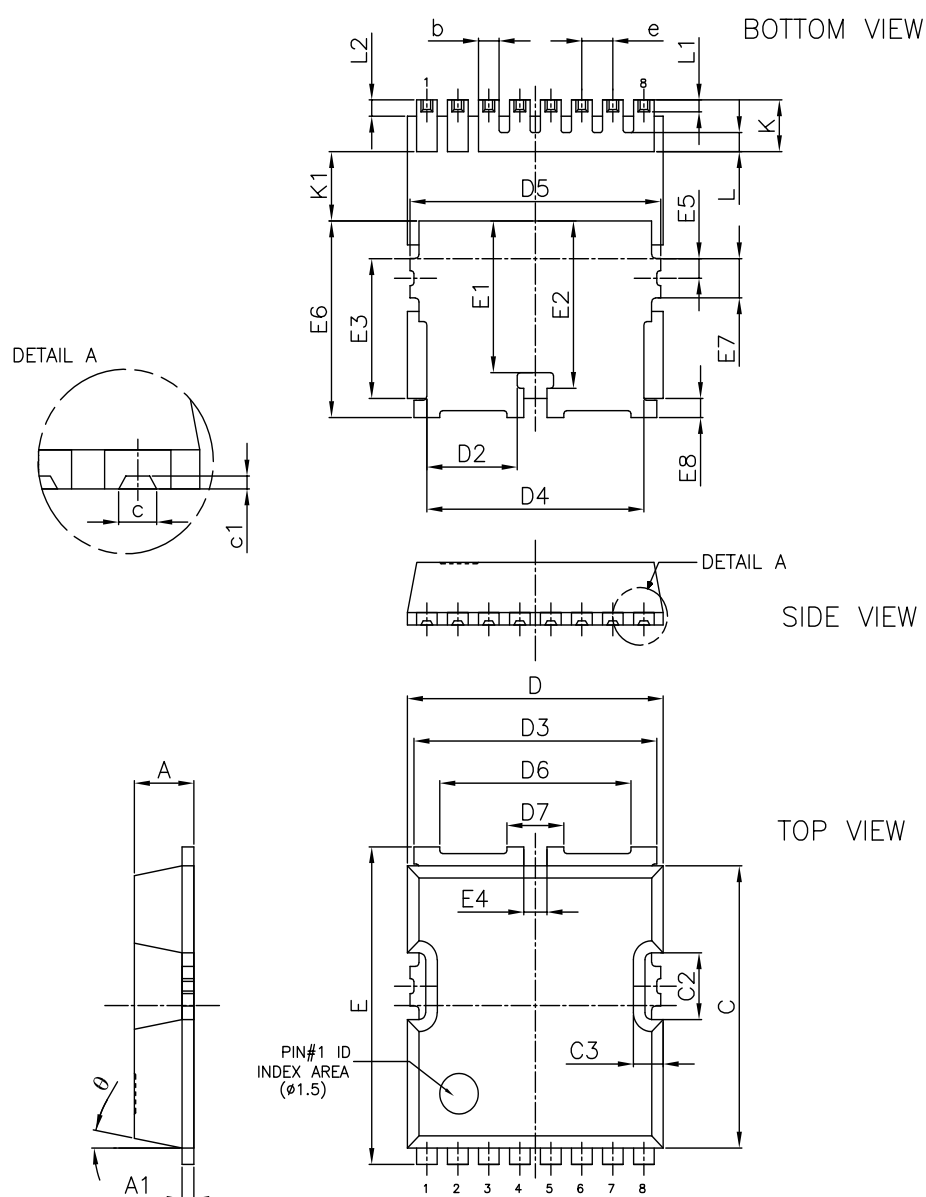
AM01473v1

4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of **ECOPACK** packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

4.1 TO-LL type A2 package information

Figure 19. TO-LL type A2 package outline



DM00276569_5_type_A2

Table 8. TO-LL type A2 package mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	2.20	2.30	2.40
A1	0.40	0.48	0.60
b	0.70	0.80	0.90
c		0.46	
c1		0.15	
C	10.28	10.38	10.48
C2	2.35	2.45	2.55
C3		1.16	
D	9.80	9.90	10.00
D2	3.30	3.50	3.70
D3	9.30	9.40	9.50
D4	8.20	8.40	8.60
D5	9.50	9.70	9.90
D6		7.40	
D7		2.20	
e		1.20	
E	11.48	11.68	11.88
E1		5.58	
E2		6.15	
E3		5.14	
E4		0.90	
E5		0.72	
E6	7.03	7.23	7.43
E7		1.44	
E8	0.50	0.70	0.90
K	1.70	1.90	2.10
K1	2.40		
L		0.70	
L1		0.44	
L2	0.40	0.60	0.80
θ		11°	

Technical drawing of a mechanical part, showing a side view (top) and a front view (bottom).

Side View (Top):

- Overall width: 10.10
- Overall height: 1.50 + 2.80 + 3.70 = 8.00
- Top flange width: 0.70
- Bottom flange width: 9.70

Front View (Bottom):

- Overall width: 6.85
- Overall height: 2.80
- Number of features: 8
- Feature 1 width: 0.85 (x8)
- Feature 2 width: 0.35 (x7)
- Feature 3 width: 0.80

DS13208 - Rev 2

4.2 TO-LL packing information

Figure 21. Carrier tape outline and dimensions

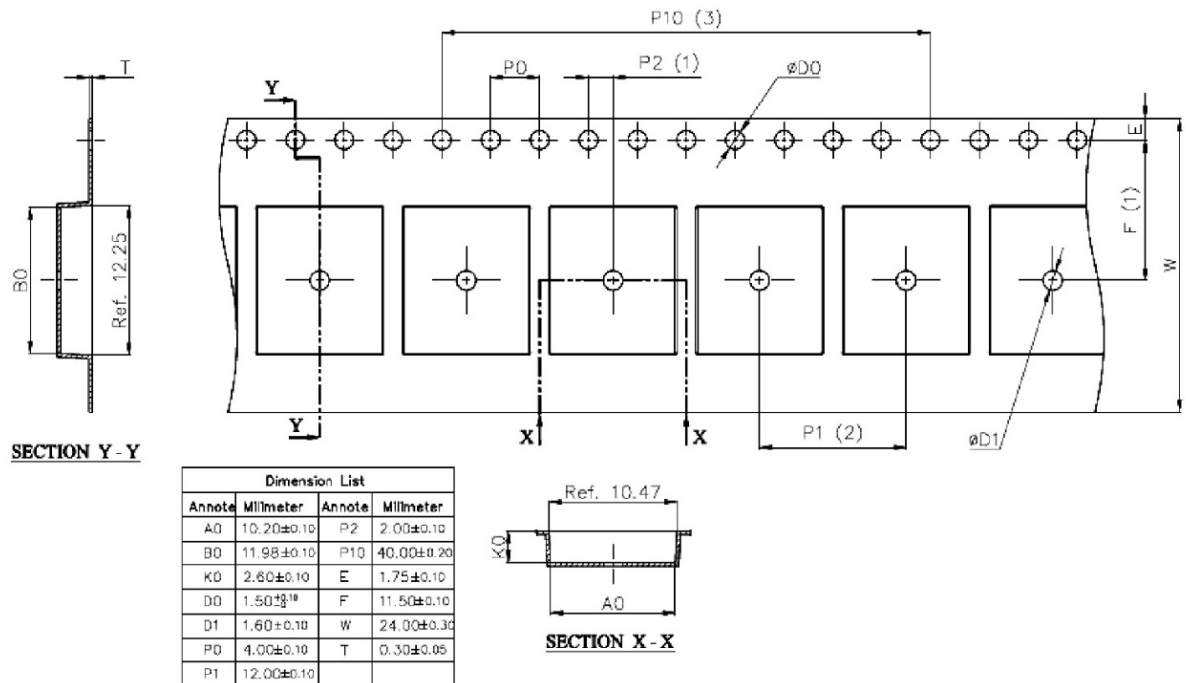


Figure 22. Reel outline and dimensions

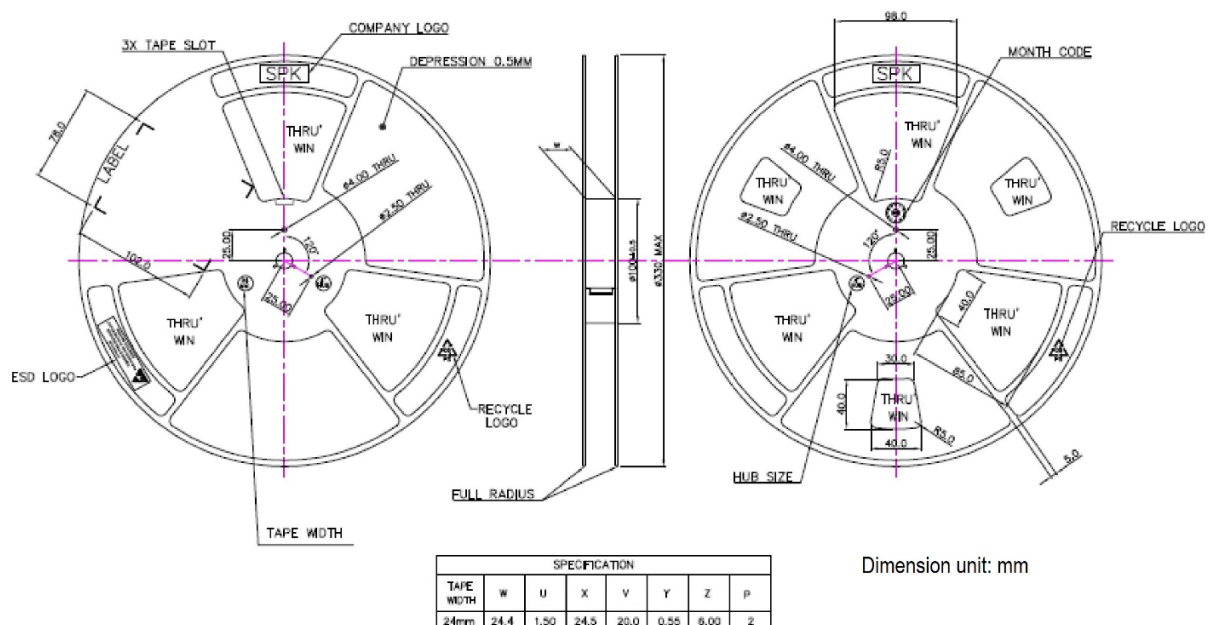
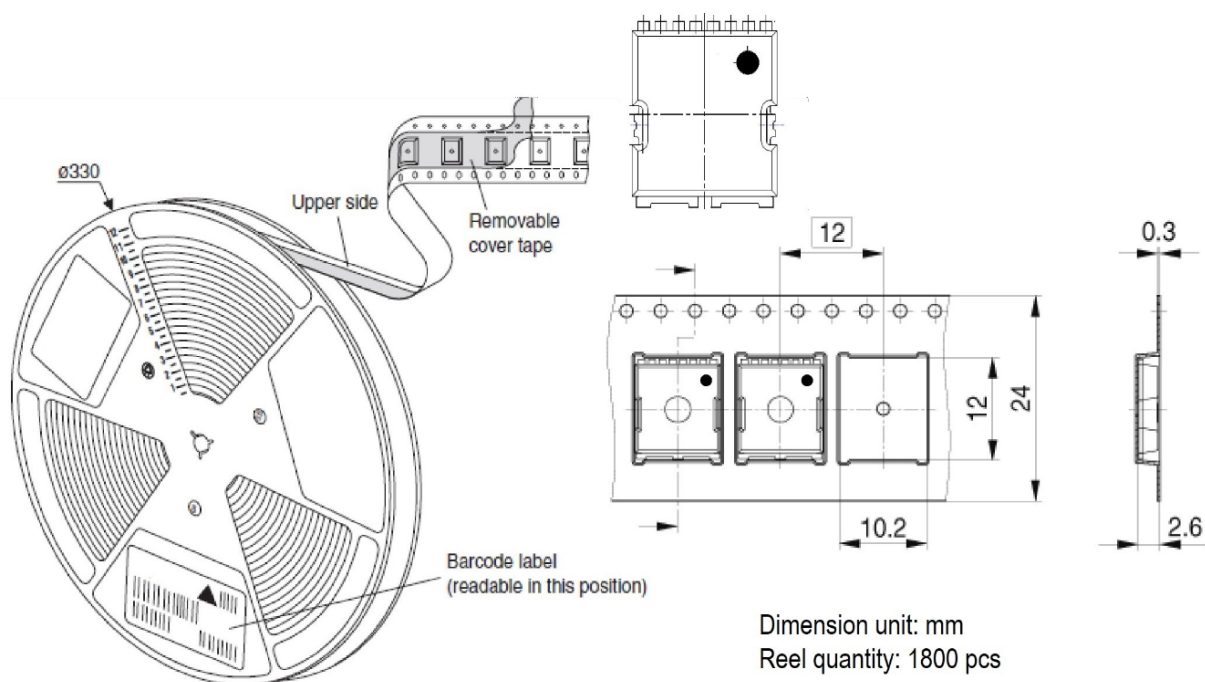


Figure 23. TO-LL orientation in tape pocket



Revision history

Table 9. Document revision history

Date	Version	Changes
18-Dec-2019	1	First release.
29-Apr-2021	2	Updated title and Device summary in cover page. Updated Section 4 Package information . Minor text changes.

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